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SC12866TP

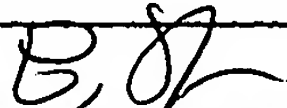
PTO/SB/08A (04-03)

Substitute for form 1449A/PTO  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)		<i>Complete If Known</i>	
		Application Number	10/662832
		Filing Date	
		First Named Inventor	Michael J. Rendon et al.
		Group Art Unit	2845
Examiner Name			
Sheet 1 of 1	Attorney Docket Number	SC12866TP	

U. S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code <sup>2</sup> (if known)			
EJ	AA	US -2003/0042551	03-06-2003	Agnello et al.	
	AB	US -2002/0197806	12-26-2002	Furukawa et al.	
	AC	US -6,472,283	10-29-2002	Ishida et al.	
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FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
EJ	AM	VAN MEER, Hans et al.; "70 nm Fully-Depleted SOI CMOS Using a New Fabrication Scheme: The Spacer/Replacer Scheme"; Symposium on VLSI Technology Digest of Technical Papers; 2002; 2 pp; IEEE	

Examiner Signature		Date Considered	9-1-04
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